

Part 2: Process Fundamental Technology

Real men own fabs.

W.J. Saunders III, Chairman and CEO of Advanced Micro Devices Inc.

Building a new fab is like playing Russian roulette. When you build a fab, you hold the gun to your head, pull the trigger and wait three years to see if you're dead.

Unnamed IC company executive. (Integrated Circuit Design, September 1996)

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2 process 1

Outline

- CMOS Processing
 - Wafer Production
 - CMOS Process Outline
 - Photolithography
 - Material Deposition & Removal
 - Oxide Growth & Removal
- Layout Design
 - Layer map
 - Layout examples
 - Stick diagrams
- Design Rules
 - Only very briefly

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Course Material for 02-Process

Chapter 2, 2nd ed.

P = primair, I = Illustratie, O = overslaan

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CMOS Processing

- Overview
- Photolithography
- Material Deposition & Removal
- Oxide Growth & Removal

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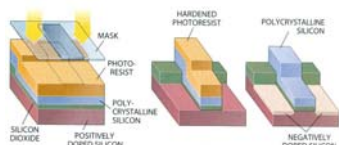
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IC Technology



- cleaning
- deposition
- apply photoresist
- exposure
- development
- etching
- remove resist



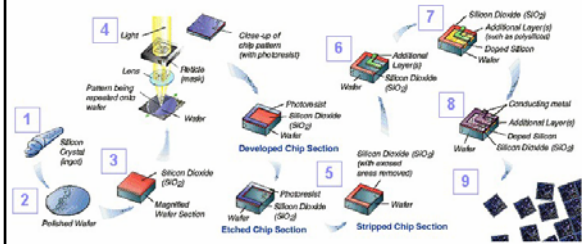
Multiple cycles, 100's STEPS in total

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Another Overview of Semiconductor Processing



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Wafer Processing – Czochralski Method

- Start with crucible of molten silicon ($\approx 1425^\circ\text{C}$)
- Insert crystal **seed** in melt
- Slowly rotate/raise seed to form single crystal **boule**
- After cooling, slice boule into **wafers** & polish

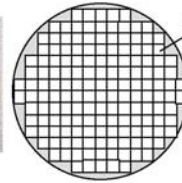
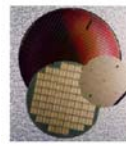


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Wafer Structure



300 mm
wafer
(sematech)

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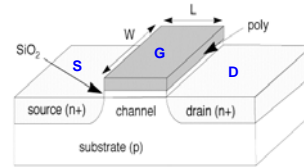
CMOS Process Outline

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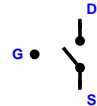
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MOS Transistor



Position of switch depends on gate to source voltage



V _{GS}	NMOS	PMOS
hi	closed	open
lo	open	closed

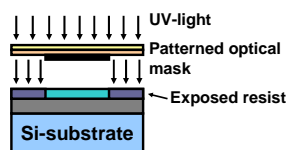
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How Patterns on a Chip are Created

- Basic Principle: **Photolithography**
 - Like **projecting an image** through a photographic negative (or positive)
- Coat wafer with **Photoresist**
- Shine **UV light** through glass mask
- **Develop**: dunk in acid to remove exposed areas ("pos.") or unexposed areas ("neg.")

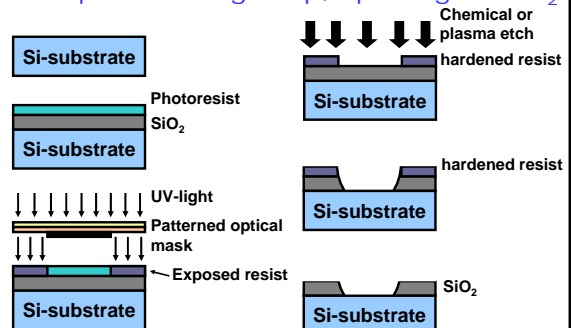


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Example: Etching Step, opening of SiO₂



Etching is for removal of material, similar masking principles for deposition (adding of material)

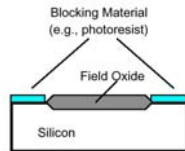
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Oxidation

- SiO_2 formed by oxidation
 - Wet oxidation: heat with water (900°C - 1200 °C)
 - Dry oxidation: heat with pure oxygen (1200 °C)
- Oxide occupies more volume
- Alternative: deposition



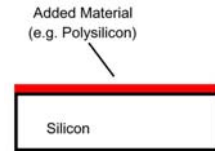
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Adding Materials

- Add materials on top of silicon
 - Polysilicon
 - Metal
 - SiO_2
- Methods
 - Vapor deposition
 - Sputtering (Metal ions)



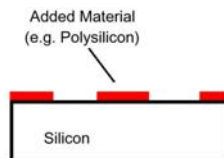
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Patterning Added Materials

- Add material to wafer
- Coat with photoresist
- Selectively remove photo resist (PR), after exposure through mask
- Remove unprotected (by PR) material
- Remove remaining PR



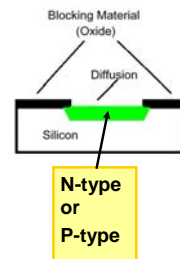
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Diffusion

- Modify electrical properties of Si:
 - N-type (extra electrons)
 - or p-type (fewer electrons \leftrightarrow extra holes)
- Introduce **dopant** via epitaxy or ion implant e.g. Arsenic (N), Boron (P)
- Allow dopants to **diffuse**
- Block diffusion in selective areas using oxide or PR (photo-resist)
- Diffusion spreads both vertically, horizontally



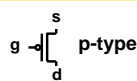
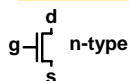
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CMOS – Complementary Metal Oxide Semiconductor Technology

2 Distinct Transistor Types



- “on” when V_g is high
- With n-type s/d
- Electrons (n) as carrier
- Built in p-type Si
- “on” when V_g is low
- With p-type s/d
- Holes (p) as carrier
- Built in n-type Si



n-well (for PMOS) in p-type substrate (for NMOS)

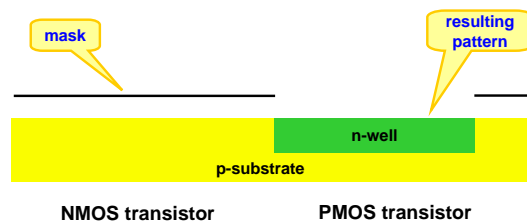
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Outline of Process Flow

First place **n-well** to provide properly-doped substrate for n-type, p-type transistors :



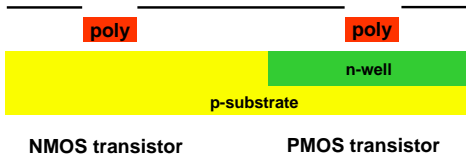
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Outline of Process Flow, cont'd

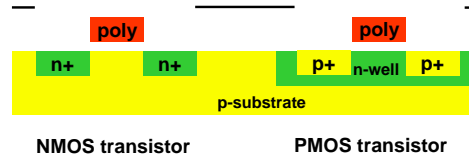
Pattern **gate** next, to later act as a mask for source and drain diffusions:



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Outline of Process Flow, cont'd

Add **s/d diffusions**, with self-masking by poly gate:



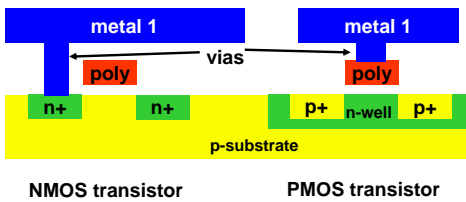
Self-masking: Poly also works as a mask, ensuring good alignment of s/d to gate

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Outline of Process Flow, cont'd

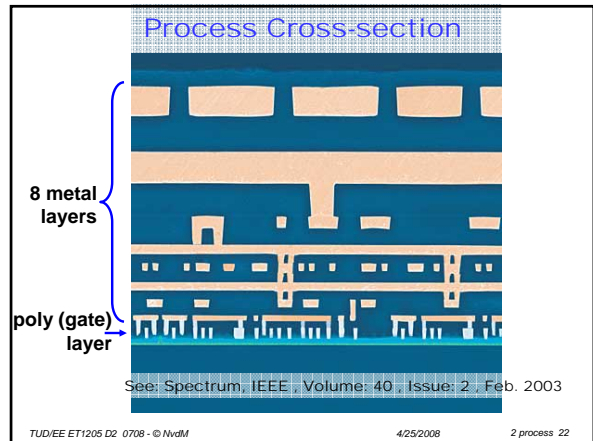
Start adding **metal layers**:

Via: contact hole between metal layers



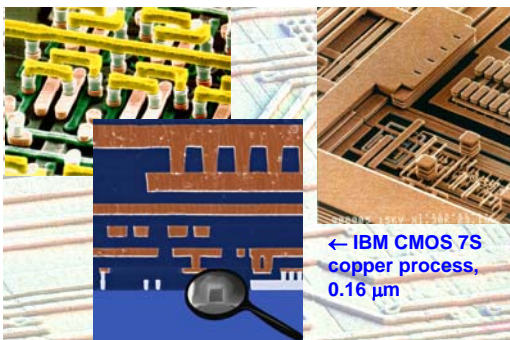
Similar for subsequent metal layers

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Interconnect Examples (motorola, ibm)



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IC Recipe Precisely Fixed

- Process conditions (temperature, time, concentration, ...) **very critical**
- Many **strong compatibility** issues of materials and processes
- Very expensive and **difficult to tune**
- Very expensive **equipment** and facilities
- Need **Billions** of turnover for break-even

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Complex Lithographic Process

- Example: ASML TWINSCAN™ XT:1250
- Sub wave length Lithography
193 nm KrF Laser (Deep UV)
- 65 nm resolution
- < 8 nm overlay
- > 85 WpH (300 mm)
- DOF ~ 0.50 μm (1: 600.000)
- price around 5M€
- www.asml.com
- Modern wafer fab: > 5-10B\$

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Compare Stepper Wafer Size and Resolution to NL scale

- Wafer size: Ø 300mm
- Resolution: 45nm
- Netherlands: 40.000 km² ~ 200km x 200km

300mm	1	45nm
200km	667x10 ³	3cm

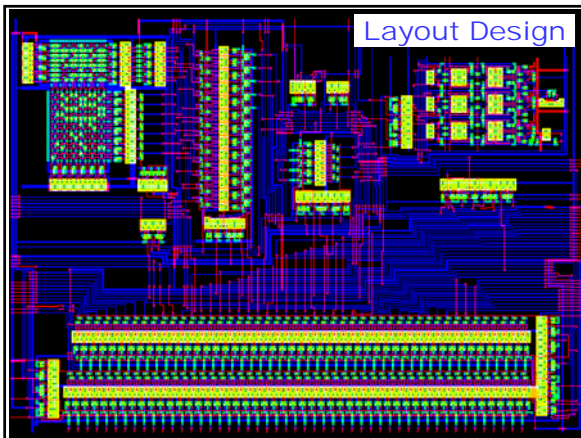
A 'magnified' waferstepper could 'print' the Netherlands with a resolution of 3 cm in 42 sec.

Equivalent to a 44 terabit camera (6.7x6.7 Mega pixel)

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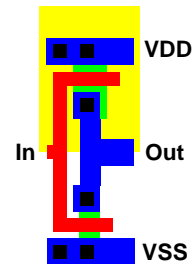
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Layout Design

Layout Design Concepts

- Layer map
- Layout examples
- Stick diagrams



You should be able to understand such a drawing as well as simpler drawings called 'stick diagram'

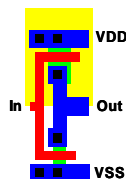
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Layout Design

- Layout is design of **fabrication masks**
- Each mask is drawn in **different color**
- Layout is not a free-form drawing
 - Most often: **Manhattan Layout** (rectangular)
 - Sometimes 45-degree angles
 - Curved geometry only for special applications
- Layout should obey **Design Rules**



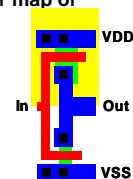
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Layer Map

- **Layers** are assigned **colors** and/or **patterns**, not always 1 to 1
- Is a matter of **convention**
- **Site-dependent, process dependent, tool dependent**
- Be prepared to **reverse-engineer** layer map of **unknown layouts**







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Our Reduced CMOS Layer Map

- yellow  **nwell** – place for P-transistors
- green  **active** – source and drain regions
- red  **polysilicon** – gate material
- blue  **metal 1** – first interconnect metal
- black  **contact, via** – hole in interlayer oxide

- Our layouts will be composed of these colors
- Or equivalent B/W patterns
- Compare to / instead of color plate 1
- **Note:** active = active area = diff = diffusion, well \approx tub

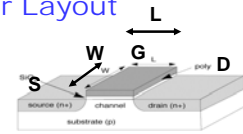
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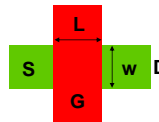
2 process 31

Transistor Layout

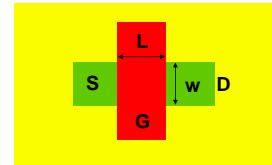
n-well (p-sub)



n-type



p-type



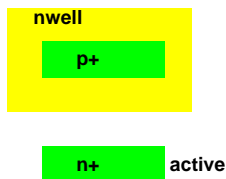
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Polarity of Active Area

- **Active layer** or active area is the source/drain implant layer (area). Usually abbreviated as 'active' only.
- Normally, a so-called **select mask** determines polarity of active
- See color plate 5
- We will implicitly define polarity of active by n-well
- Or we will even omit the nwell and use the context

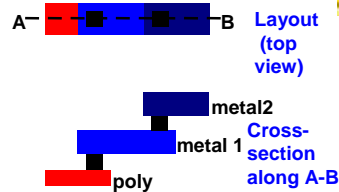


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Contact Holes and Vias

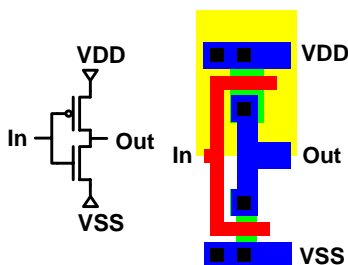


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Inverter Layout



Main difficulty: you need to guess/extrapolate covered portions of the layout (e.g. green under blue)

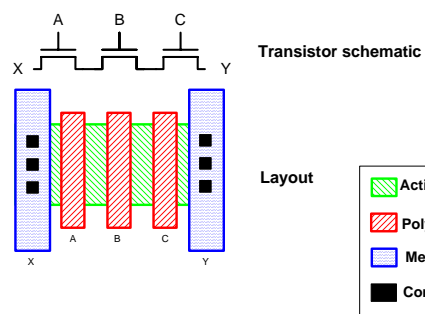
Given such a layout, you should be able to draw the circuit on the left, as well as the different cross-sections

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From Schematic to Layout



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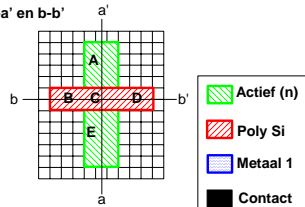
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Exercise

Zie onderstaande lay-out van een transistor.
Geef voor ieder van de aansluitingen gate, source, drain aan uit welke letters A-E (zie de layout) het gebied bestaat.

G:
S:
D:

Teken een doorsnede langs a-a' en b-b'



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Stick diagrams

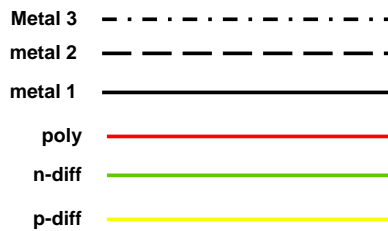
- A stick diagram is a **cartoon** of a layout.
- Does show components/vias but only **relative placement**.
- Does **not** show **exact placement**, transistor sizes, wire lengths, wire widths, tub boundaries, some special components.

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Stick layers



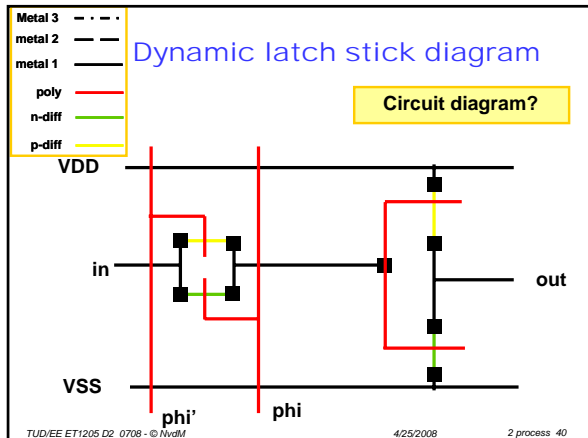
- **Caution:** stick diagrams don't display wells, use different colors for active area to distinguish between n-diff and p-diff

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Dynamic latch stick diagram



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Design Rules

- The fabrication process will suffer from **tolerances**
- Chip features will have a practical **minimum size** to allow them to be fabricated reliably enough (with high enough **yield**)
- This is captured into a set of precise **Design Rules**
- Modern processes have terribly complex set of design rules as a compromise between **flexibility** and **manufacturability**
- We will **ignore** this subject
- But you will have to understand it during **OP** next year.

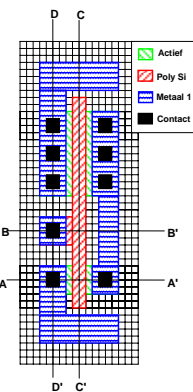
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Zie bijgaande layout van een CMOS inverter

- Teken doorsnedes langs A-A', B-B' en C-C'
- Welke van de twee transistoren is (vermoedelijk) de P-MOS transistor (waarom?)
- Teken voor deze keuze de layout van de N-well.
- Geef in de layout aan waar de Vss en Vdd aansluitingen zitten.
- Teken het transistor schema, met l/w ratio's



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Summary

- CMOS Processing
 - Photolithography
 - Material Deposition & Removal
 - Oxide Growth & Removal
- CMOS Process Outline
- Layout Design
 - Layer map
 - Layout examples
 - Stick diagrams
- Design Rules
 - Why we need design rules